


<b>Search Notes</b>  	<b>Application/Control No.</b>  10510679	<b>Applicant(s)/Patent Under Reexamination</b>  MIYAKI ET AL.
	<b>Examiner</b>  Nathan W Ha	<b>Art Unit</b>  2814

SEARCHED			
Class	Subclass	Date	Examiner
438	106-113; 257/734-738, 678, 690-691, E33.056	9/23/07	NH

SEARCH NOTES		
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INTERFERENCE SEARCH			
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